

<b>Notice of References Cited</b>	Application/Control No. 10/665,435	Applicant(s)/Patent Under Reexamination YU ET AL.	
	Examiner Thuy V. Tran	Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0151565 A1	08-2003	Kim et al.	345/60
*	B	US-2002/0180718 A1	12-2002	La, Kwang-Hyun	345/204
*	C	US-6,693,609	02-2004	Lee et al.	345/63
*	D	US-6,473,061	10-2002	Lim et al.	345/60
*	E	US-5,943,032	08-1999	Nagaoka et al.	345/63
*	F	US-5,856,823	01-1999	Kimoto et al.	345/600
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.